Supplementary Information

Atomic layer deposition of a Sb₂Se₃ Photo-absorber Layer using Selenium Dimethyldithiocarbamate as new Se precursor

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SI-1: Literature review of Se precursors investigated for metal selenide ALD

| Sr. | Se Precursor | Vapor | Decompos | Safety | Availability | Referen | Note |
|-----|-------------------------------------|------------|------------|--------------|--------------|---------|------------------------------|
| No | | pressure | ition temp | quotient | | ce | |
| 1. | H ₂ Se | High | | Extremely | Limited | 1,2 | NA |
| | | (gaseous | | toxic and | (due to | | |
| | | precursor | | flammable | toxicity) | | |
| 2. | Diethylseleniu | NA | Decompos | Extremely | Commercial | 3 | Not a ideal ALD precursor. |
| | $m + H_2$ | | ed Se | toxic and | ly available | | Limited ALE report. |
| | | | vapors | flammable | but with | | Not suitable for most |
| | | | only | | limited | | exchange reaction with most |
| | | | | | usage | | often used metal precursors |
| 3. | $Se + H_2$ | NA | NA | Extremely | Commercial | 4 | Not an ideal ALD precursor. |
| | | | | toxic and | ly available | | Limited ALE report. |
| | | | | flammable | but with | | Not suitable for most |
| | | | | | limited | | exchange reaction with most |
| | | | | | usage | | often used metal precursors |
| 4. | (R ₃ Si) ₂ Se | Data not | Data not | Data not | Commercial | 5,6 | Lab scale synthesis reported |
| | | available | available | available | ly NOT | | with 83% yield. |
| | | | | | available | | |
| 5. | Selenium | Low, solid | 200°C | NO, unless | YES | This | |
| | Dimethyldithi | precursor | | exposed to | | report | |
| | ocarbamate | | | large amount | | | |

SI-2: Substrate preparation:

Commercially available TEC 7 fluorine doped tin oxide (FTO) coated conducting glass substrates (from Dyesol, Australia) are used as substrates for ex-situ measurement purposes. The substrates are ultrasonically cleaned in acetone, alconox solution, DI water and isopropyl alcohol (IPA) sequentially for 15 min each. Dense TiO_2 (d- TiO_2) blocking layer is then spin coated at the spin program of 2500 rpm for 60 sec and then sintered in air at 500°C for 1 hr followed by natural cooling. The solution used for d- TiO_2 spin coating is prepared in two steps where step one contains 369 μ L of TTIP to 2.53 mL of IPA stirred vigorously for 5 min. In the second step, a solution of 35 μ l HCl in 2.53 mL of IPA is then added dropwise and stirred for 2 hours before spin coating on the FTO substrates. A mesoporous TiO_2 (p- TiO_2) is then spin coated on d- TiO_2 layer using a commercially available 30 NRD titania paste (from Dyesol, Australia) where the paste is diluted in an anhydrous ethanol (from Sigma Aldrich) in 1:3 weight ratio and spin coated at 1000 rpm for 60 sec. The samples are then sintered again in air at 500°C for 1 hr followed by natural cooling.

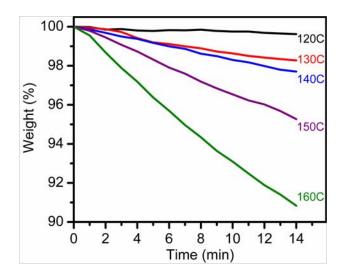


Figure SI-1: Isothermal TGA data for SDMDTC in N_2 ambience at different temperatures namely 120°C, 130°C, 140°C, 150°C and 160°C.

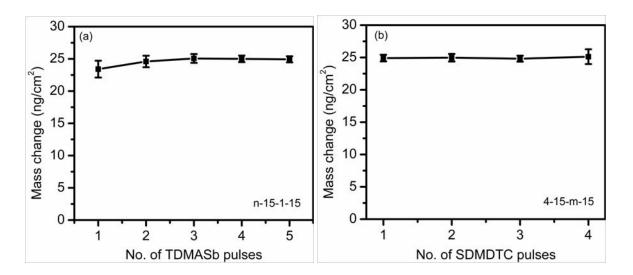


Figure SI-2: Mass changes versus precursor exposures of (a) TDMASb and (b) SDMDTC for self-saturation studies during Sb_2Se_3 deposition.

Figure SI-2(a) represents the mass gain per cycle as a function of TDMASb exposure where single pulse of 1 sec is kept constant in the SDMDTC half cycle. The surface sites are seen to saturate completely with minimum of 3 TDMASb exposures of 1 sec each. However, growth rate seems to saturate with a single exposure of 1 sec of SDMDTC in the second half cycle as shown in figure SI-2(b). Hence, 3 exposures of TDMASb and single exposure of SDMDTC are required to saturate the surface reactions for each ALD cycle producing a steady state mass gain of ca. 25 ng/cm^2 . This corresponds to the growth rate of ca. 0.28 Å/cyl as the saturated growth of Sb₂Se₃.

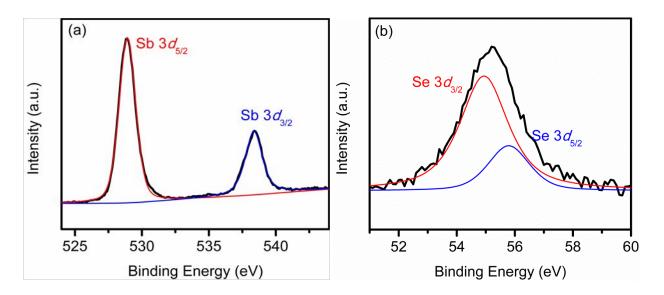


Figure SI-3: Deconvolution of high resolution core scan of (a) Sb 3d and (b) Se 3d for as-deposited samples.

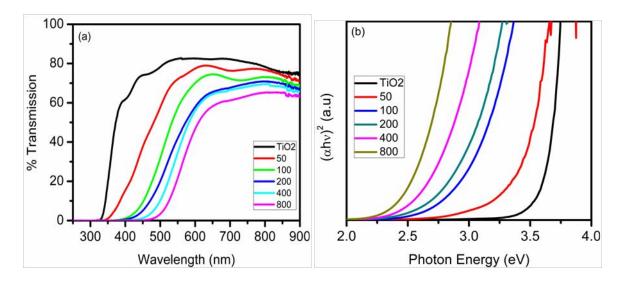


Figure SI-4: (a) Optical transmission spectra of bare and ALD Sb_2Se_3 coated TiO_2 films at 150°C and (b) the corresponding Tauc plot with n=2 for direct band gap calculations.

SI-7: Urbach energy calculation:

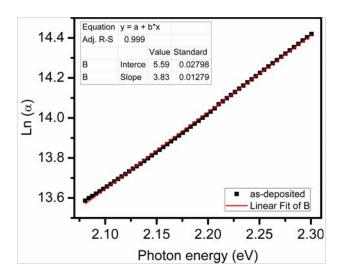


Figure SI-5: Linear fitting curve for the Urbach energy calculation of as-deposited Sb₂Se₃ ALD grown films.

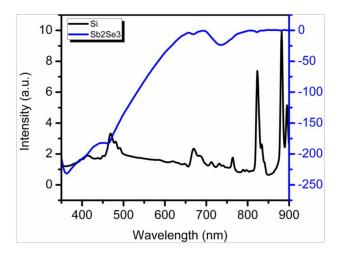


Figure SI-6: Xe light spectra measured by Si detector (black) and Sb_2Se_3 SPS spectra (blue) under the monochromatic light in the wavelength range of 900-300 nm.

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